

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 21.0002
CB Certificate No.: 50600386 ITL

Schedule Number: IECQ-L ULTW 21.0002-S Rev No.: 1 Revision Date: 2021/03/10 Page 1 of 1

Appendix-1 (50600386 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Scanning Electron Microscope (SEM) Analysis	TE3-F01
High Temperature Storage Life 高溫儲存試驗	JESD22-A103 (TE3-R01)
Halide Test 鹵化物滴定試驗	JIS-Z-3197 8.1.4.2 (TE3-C01)
Acid Value Test 酸價滴定試驗	JIS-Z-3197 8.1.4.1 (TE3-C02)
Surface Insulation Resistance, Fluxes 表面絕緣阻抗試驗	IPC-TM-650 2.6.3.3 (TE3-R02)
Surface Insulation Resistance 表面絕緣阻抗試驗	IPC-TM-650 2.6.3.7 (TE3-R03)
Electrochemical Migration Resistance Test 電子遷移試驗	IPC-TM-650 2.6.14.1 (TE3-R05)
Corrosion, Flux 銅板腐蝕試驗	IPC-TM-650 2.6.15 (TE3-R04)

Technical Reviewer of DQS:

Date: 3/10/2021



Twe Wood